

SPC-150N

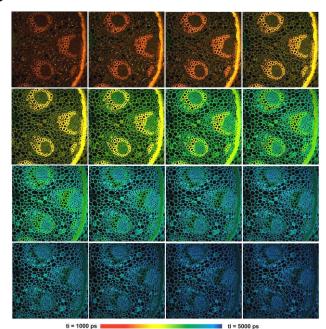
TCSPC / FLIM Module

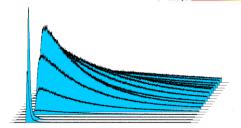
Time-Correlated Single Photon Counting Module

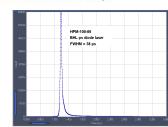
Improved version of SPC-150 TCSPC module
Input discriminator bandwidth 4 GHz
Improved resolution for ultra-fast detectors
Ultra-high IRF stability
Multi-detector / multi-wavelength capability
FLIM by bh Megapixel Technology
Mosaic FLIM mode
Multiscaler imaging mode
Photon distribution and parameter-tag modes
Parallel operation of 2, 3 or 4 modules
Time channel width down to 813 fs
Electrical time resolution (Jitter) 6.6 ps FWHM / 2.5 ps RMS
Reversed start/stop: Laser repetition rates up to 150 MHz
Saturated count rate 10 MHz

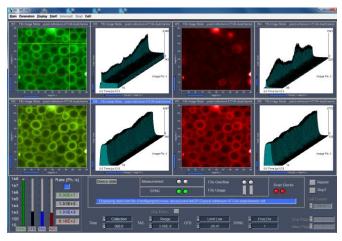
Standard fluorescence lifetime experiments
Multi-wavelength lifetime experiments
Recording of transient fluorescence lifetime effects
Single-wavelength FLIM, multi-wavelength FLIM
Fast-acquisition FLIM, time-series FLIM
Mosaic FLIM, lateral, longitudinal, temporal mosaics
FLITS

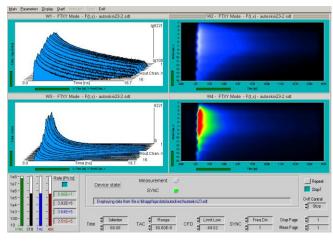
Simultaneous PLIM and FLIM
Double-exponential FRET imaging
Recording of Ca²⁺ transients
fNIRS and NIRS experiments
Single-molecule spectroscopy
FCS, FCCS, PCH
Anti-bunching experiments













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SPC-150N

TCSPC / FLIM Module

Photon Channel

Principle Discriminator Input Bandwidth Time Resolution (FWHM / RMS, electr.)
Variance in time of IRF maximum

Optimum Input Voltage Range

Min. Input Pulse Width

Threshold

Zero Cross Adjust

Synchronisation Channels

Principle

Discriminator Input Bandwidth Optimal Input Voltage Range

Min. Input Pulse Width

Threshold

Frequency Range

Frequency Divider

Zero Cross Adjust

Time-to-Amplitude Converters / ADCs

TAC Range

Biased Amplifier Gain

Biased Amplifier Offset Time Range incl. Biased Amplifier

min. Time / Channel ADC Principle

Diff. Nonlinearity, electrical

Data Acquisition (Histogram Mode)

Dead Time

Saturated Count Rate

Useful count rate

Channels / Pixel

max. Scanning Area max. Counts / Time Channel

Overflow Control

Collection Time

Display Interval Time Repeat Time

Sequential Recording Synchronisation with Scanning

Count Enable Control Experiment Trigger

Data Acquisition (FIFO / Parameter-Tag Mode)

Method

Online display

FCS calculation

Number of counts of decay / waveform recording Dead Time

Saturated count rate, peak

Sustained count rate (bus-transfer limited)
Output Data Format (ADC / Macrotime / Routing)

FIFO buffer Capacity (photons) Macro Timer Resolution, internal clock

Macro Timer Resolution, clock from SYNC input Curve Control (external Routing)

External event markers Count Enable Control

Experiment trigger

Data Acquisition, FIFO Imaging Mode

Method Online display

Synchronisation with scanner

Detector / Wavelength Channels Image resolution, 64-bit SPCM software

No of time channels No. of pixels, 1 detector channel No. of pixels, 16 detector channels

Operation Environment

Computer System Bus Connectors

Used PCI Slots

Total power Consumption

Related Products

SPC-150NX, SPC-150NXX TCSPC Modules Simple-Tau 150 compact TCSPC systems Simple-Tau 154 compact 4-channel TCSPC systems DCS-120 confocal scanning FLIM system

Constant Fraction Discriminator (CFD) 4 GHz 6.6 ps / 2.5 ps <1 ps over 50 seconds - 30 mV to - 500 mV

200 ps 0 to - 250 mV - 100 mV to + 100 mV

Constant Fraction Discriminator (CFD)

4 GHz - 30 mV to - 500 mV 200 ps 0 to -250 mV

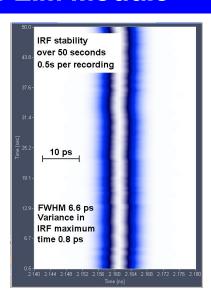
0 to 150 MHz

1-2-4 -100 mV to + 100 mV

Ramp Generator / Biased Amplifier

50 ns to 5 us 1 to 15 0 to 100% of TAC Range

3.3 ns to 5 us 813 fs 50 ns Flash ADC with Error Correction < 0.5% rms, typ. <1% peak-peak



on-board multi-dimensional histogramming process 100ns, independent of computer speed 10 MHz

5 MHz

4096 64 256x256 1024x1024 2048x2048 128 x 128 512x512 16x16 64x64 2¹⁶-1

none / stop / repeat and correct 0.1 us to 100,000 s 10 ms to 100,000 s 0.1 us to 100,000 s

Programmable Hardware Sequencer, unlimited recording by memory swapping, in curve mode and scan mode pixel, line and frame clocks from scanning device

1 bit TTL

Parameter-tagging of individual photons and continuous writing to disk Decay function, FCS, Cross-FCS, PCH, MCS traces Multi-tau algorithm, online calculation and online fit

unlimited

100 ns 10 MHz

typ. 4 MHz 12 / 12 / 4

2 M

50ns, 12 bit, overflows marked by MTOF entry in data stream

10ns to 100ns, 12 bit, overflows marked by MTOF entry in data stream 4 bit TTL

4 bit, TTL 1 bit TTL

Buildup of images from time- and wavelength tagged data

up to 8 images in different time and wavelength windows or from different modules via Frame Clock, Line Clock, and Pixel Clock pulses

1 to 16

64 256 1024 4096 x 4096 2048 x 2048 1024 x 1024 1024 x 1024 512 x 512 256 x 256 128 x 128

PC Pentium, multi-core, >8GB RAM, Windows 10

PCI

approx. 12 W from +5V, 0.7 W from +12V 240 mm x 130 mm x 15 mm

HPM-100 GaAsP and GaAs hybrid detectors

PML-SPEC and MW-FLIM multi-wavelength detectors PMC-150 cooled PMT modules id-100 SPAD detector modules

DCC-100 detector controller BDL-SMN ps diode lasers BDS-SM, -SMY, and -MM picosecond diode lasers

4096

512 x 512

Related Literature

W. Becker, Advanced time-correlated single photon counting techniques. Springer 2005. Please contact bh for availability.

W. Becker, The bh TCSPC Handbook, 7th edition. 891 pages, 1155 references. Available on www.becker-hickl.com. Contact bh for printed copies. PML-16-C 16 channel detector head for time-correlated single photon counting. User handbook. Available on www.becker-hickl.com

DCS-120 Confocal Scanning FLIM Systems, handbook. Available on www.becker-hickl.com Modular FLIM systems for Zeiss LSM 510 and LSM 710 laser scanning microscopes, handbook. Available on www.becker-hickl.com. Contact bh for printed copies.

BDL-SMN picosecond diode lasers, handbook. Available on www.becker-hickl.com Please see also www.becker-hickl.com, 'Literature', 'Application notes'